

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor(MLCC) for use in electric equipment for the voltage is ranging from 4V to 50V.

The series suitable for general electrics circuit, telecommunications, personal computers and peripheral, power circuit and mobile application. (This product is compliant with the RoHS & HF.)

2. Parts Number Code

HCL	1812	Х	106	К	050	Т	F
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)

(1)Product

Product Code	
HCL	Ceramic capacitors

(5) Capacitance Tolerance

Code Tolerance	Nominal Capacitance More Than 10 pF

(2)Chip Size

Code	Length×Width	unit : mm(inch)
1812	4.60× 3.2	0 (.181× .125)

(6)Rated Voltage

Code	Rated Voltage (Vdc)
050	50

(3) Temperature Characteristics

X	X7R	-55℃~+125℃	± 15%
	Characteristic	Range	Coefficient
Code	Temperature	Temperature	Temperature

(7)Tapping

Code	Type
Т	Tape & Reel

(4)Capacitance

unit :pico farads(pF)

Code	Nominal Capacitance (pF)
106	10,000,000.0

^{※.} If there is a decimal point, it shall be expressed by an English capital letter R

(9)Thickness

Code	Thickness T (mm)
F	2.00±0.20

3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

С	lass	Characteristic	Tolerance	Nominal Capacitance
	П	X7R	K (± 10.0 %)	E-3, E-6 series

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			2.2			4.7					
E- 6	1	.0	1	.5	2	.2	3	.3	4	.7	6.	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.		
П	X7R (X)	-55℃ ~ +125℃	25℃		

5. Storage Condition

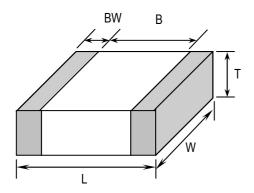
Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 12 months max.

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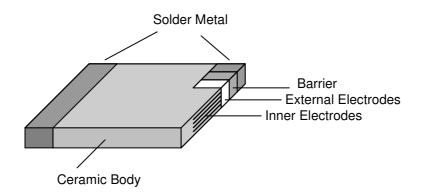
6. Dimensions

6.1 Configuration and Dimension:



					Unit:mm
TYPE	L	W	Т	B (min)	BW (min)
1812	4.60± 0.30	3.20± 0.30	2.00± 0.20	2.50	0.30

6.2 Termination Type:



7. Performance

No.	lte	em	Specification			Test Condition		
1	Vis	sual	No abnormal exterior appearance			Visual Inspection		
2	Dime	ension	See Pa			Visual Inspection		
3		lation stance	500/C	Ω min.		Applied Voltage: Rated Voltage Charge Time: 60±5 sec. Charge-Discharge current shall be less than 50mA current.		
4	Capac	citance	Within	The Specified Tol	erance	Class II ∶		
5	Tan δ	Class	X7R: 1	0% max.		Char	Frequency	Voltage
		П				X7R	1KHz±10%	1.0±0.2Vrms or 0.5±0.2Vrms
						then place room	emperature at 150 temp. for 24±2hr. individual parts.	±5℃ for 30min
6		anding tage	No die breakd	lectric breakdown lown	or mechanical	250% of the rated voltage for 1~5 sec. charge/discharge Current is less than 50mA.		
7	Temperatur		Char.	Temp. Range	Cap. Change(%)	Class II:		
	Capacitanc		X7R	-55℃~+125℃	± 15%	C2-C1 ×100%		00%
	Coefficient					C1:Capacitance At Standard Temperature(25°C) C2: Capacitance At Test Temperature (T2)		erature(25°€)
						0.2Vrms shall be applied.		
8		e Strength nination	No indication of peeling shall occur on the terminal electrode.		Pull force shall b ≤ 06035N(± > 060310N(= 1.0 Kg·f)	l second.	
9	to	Appear- ance	No mechanical damage or capacitance change more than the following table.		The board shal mm/sec.	l be bend 1.0mm v	vith a rate of 1.0	
	Flexure of Substrate C-Meter		Char.	Capacitance Change		45±1mm	Aeter 45±1mm	Bending Limit

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No.	Ite	m	S	pecification		Test Condition	
10	Solder	Solderability More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve.		Solder Temperature: 245±5°C Dip Time: 5 ± 0.5sec Immersing Speed: 25±10% mm/s Solder: Lead Free Solder Flux: Rosin Preheat: At 80~120°C for 10~30sec.			
11	Resistance To Soldering Heat	Appear- ance Capacit- ance Tan δ Class II Insulation Resistance	No mechanical damage shall occur. Class II ≤ ±7.5% of initial value X7R X7R: 10% max. To satisfy the specified initial value		Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat treatment at 150 ±0/-10°C before initial measure. Preheat: at 150± 10°C for 60~120sec. Dip: solder temperature of 260± 5°C Dip Time: 10 ± 1sec. Immersing Speed: 25±10% mm/s Flux: Rosin Measure at room temperature after cooling for Class II: 48 ± 4 Hours		
12	Tempera ture Cycle	Appear- ance Capacit- ance Tan δ	No mechanical dam Class II X7R X7R: 10% max.	age shall occur. ≤ ±7.5% of initial value	Class II: 48 ± 4 Hours Class II capacitor shall be set for 48±4 hours a room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Capacitor shall be subjected to five cycles of		
		Class II Insulation Resistance	To satisfy the specif	o satisfy the specified initial value		Temp.(°C) Min Rated Temp. +0/-3 25 Max Rated Temp. +3/-0 25 ure at room temperature as II: 48 ± 4 Hours	Time(min) 30 3 30 30 30 30
13	Humidity	Appear- ance Capacit- ance Tan δ Class II Insulation Resistance	No mechanical dam Characteristic X7R X7R: 20% max. 50/C Ω min.	age shall occur. Cap. Change ≤ ±12.5% of initial value	Class II : 48 ± 4 Hours Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Temperature : 40± 2°C Relative Humidity : 90 ~ 95%RH Test Time : 500 Hrs Max. Measure at room temperature after cooling for Class II : 48 ± 4 Hours		

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No.	Ite	m	Spe	cification	Test Condition	
14	Humidity Load	Appear- ance	No mechanical dama	ge shall occur.	Class ☐ capacitors applied DC voltage of the rated voltage is applied for one hour at maximum	
		Capacit- ance	Characteristic X7R	Cap. Change ≤ ±12.5% of initial value	operation temperature ± 3°C then shall be set for 48± 4 hours at room temperature and the initial	
		G00	7,711		measurement shall be conducted. Applied Voltage :Rated Voltage	
		Tan δ Class ${ m II}$	X7R: 20% max.		Temperature : 40± 2°C Relative Humidity : 90 ~ 95%RH	
		Insulation Resistance	25/C Ω min.		Test Time: 500 Hrs Max. Current Applied: 50 mA Max.	
					Measure at room temperature after cooling for Class II: 48 ± 4 Hours	
15	High Temperature	Appear- ance	No mechanical dama	ge shall occur.	The capacitors applied DC testing voltage is applied for one hour at maximum operation	
	Load	Capacit-	Characteristic	Cap. Change	temperature ±3℃ then shell be set for 48± 4	
	(Life Test)	ance	X7R	≤ ±12.5% of initial value	hours at room temperature and the initial	
		Tan δ	X7R: 20% max.		measurement shall be conducted.	
		Class II			Applied Voltage: Rated Voltage	
			50/C Ω min.		Temperature: max. operation temperature Test Time: 1000 Hrs Max.	
		Resistance			Current Applied: 50mA Max	
					Measure at room temperature after cooling for	
					Class II: 48 ± 4 Hours	
16	Vibration	Appear- ance	No mechanical dama	ge shall occur	Solder the capacitor on P.C. board.	
	Capacit- ance Tan δ Class II Capacit- by Within the specified tolerance To satisfy the specified initial value		Vibrate the capacitor with amplitude of 1.5mm P-P changing the frequencies from 10Hz to 55Hz and back to 10Hz			
			in about 1 min.			
		Insulation Resistance	To satisfy the speci	fied initial value	Repeat this for 2 hours each in 3 perpendicular directions.	

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Fig.1
P.C. Board for Bending Strength Test

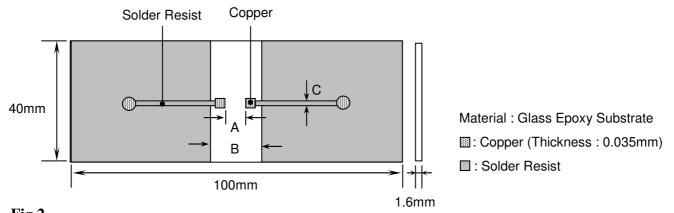
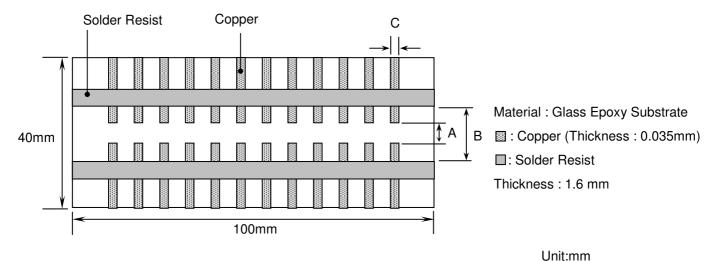


Fig.2
Test Substrate



			•
Type	A	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

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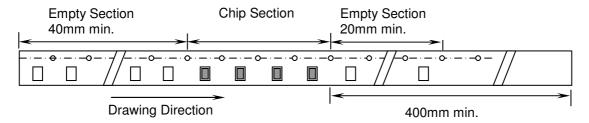


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/0805	
Material	T≦0.33mm	T≦0.55mm	T≦1.00mm	T>1.00mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	
Material	T≦1.00mm	1.00mm < T ≦ 1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel

Tape	1808/1210						
Material	T≦1.25mm	1.25mm < T ≦ 2.40mm	T>2.40mm				
Paper	NA	NA	NA				
Plastic	3000 pcs/Reel	2000 pcs/Reel	500/1,000 pcs/Reel				

Tape	1812/2211/2220		1825	2208	
Material	T≦2.20mm	T>2.20mm	T≦2.20mm T>2.20mm		T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

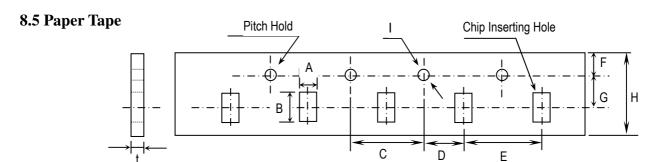
 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

8.4.2 Measure Method



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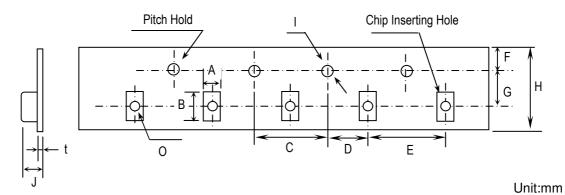


Unit:mm

TYPE	Α	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Type	Α	В	С	D	Е	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				

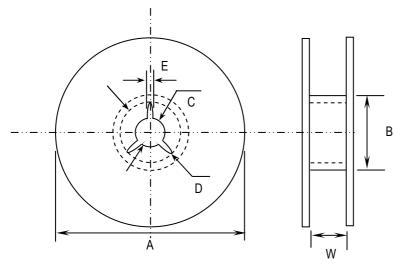


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Туре	G	Н		J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Type	А	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



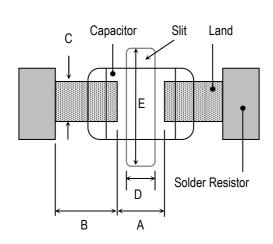
Precautionary Notes:

1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

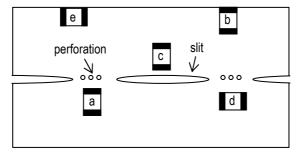
Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table: 2.1 Size and recommend land dimensions for reflow soldering



EIA Code Chip (mm)		Land (mm)					
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		1
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		-
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.
Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

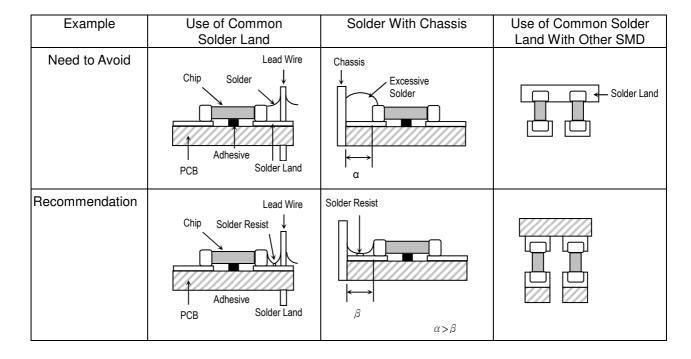
Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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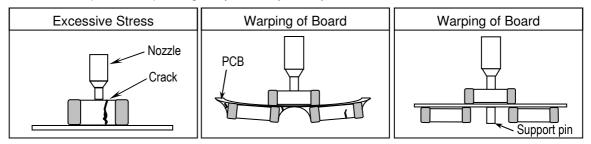


2.3 Layout Recommendation

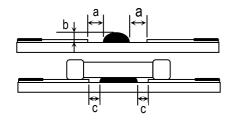


3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example: 0805 & 1206

а	0.2mm min.
b	70 ~ 100 μm
С	Do not touch the solder land

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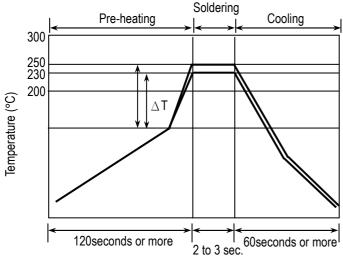


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to $250\,^{\circ}$ C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.($^{\circ}\mathbb{C}$)
1206 and Under	$\Delta T \le 100 \sim 130 \text{ max}.$

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

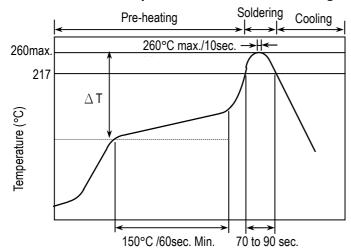
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (ΔT) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3 °C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



★ The cycles of soldering : Twice (max.)

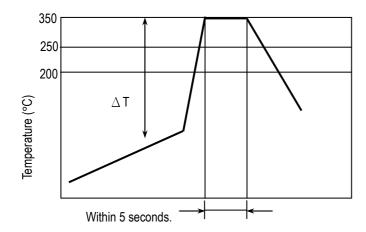
Soldering Method	Change in Temp.(°C)
1206 and Under	∆ T ≦ 190 °C
1210 and Over	∆ T ≦ 130 °C

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	∆ T ≦ 130 °C

How to Solder Repair by Solder Iron

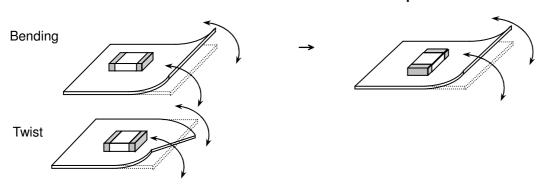
- 1) Selection of the soldering iron tip
 - The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.
- 2) recommended solder iron condition
 - a.) Preheating Condition: Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 °C to perform the process within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack

Lower potential of crack



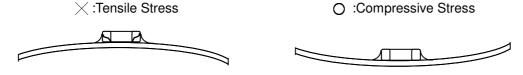
5.2 There is a potential of crack if board is warped due to excessive load by check pin



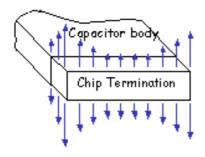
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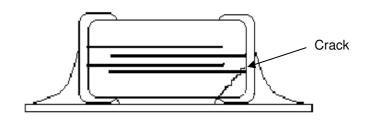


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



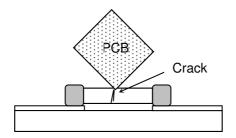


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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